

[METHODOLOGY FOR PLACEMENT BASED ON CIRCUIT FUNCTION AND LATCHUP SENSITIVITY]

Abstract

A structure, apparatus and method for circuits to minimize sensitivity to latch. The method includes, for example, identifying element density of at least one functional circuit block and element attributes of elements associated with the at least one functional circuit block. An element density function parameterized from the element attributes is formed. The placement of the at least one functional circuit block is modified relative to other functional circuit blocks based on the element density function to substantially eliminate latching effects in a circuit.